

# 15W Full-Bridge Power Stage with Voltage/Current Demodulation for High-Integrated Wireless Power Transmitter

## 1 Descriptions

The SC5004 is a highly integrated wireless power transmitter analog front end that contains all of the analog components required to implement a WPC compliant transmitter. The SC5004 integrates a full-bridge power driver with MOSFETs, current sense amplifier, bootstrap circuit, communication demodulator, linear regulator and protection circuit. The SC5004 can work with transmitter controller to create a high-performance wireless power transmitter that complies with both the WPC V1.2.4 Extended Power Profile (EPP) and Baseline Power Profile (BPP). Once an EPP receiver is detected, the transmitter will provide with up to 15W of output power. If a BPP receiver is present, the transmitter will deliver only up to 5W of output power.

The system supports foreign object detection (FOD) by continuously monitoring the amount of power transferred and comparing that to the amount of received power, as reported by the receiver. In order to do this, the SC5004 measures the input DC current very accurately using a current sense amplifier. Besides, the SC5004 also supports input under-voltage lockout (UVLO), over-current protection (OCP), short-circuit protection (SCP) and over-temperature protection (OTP). These protections further enhance the reliability of the total wireless power transmitter system.

The SC5004 is available in a compact 4 x 4 mm FCQFN package.

## 2 Features

- Support 5V/9V/12V input voltage
- Support up to 15W output power
- Integrated voltage and current demodulation
- Integrated 5V LDO for powering MCU
- Integrated four ultra-low Ron FETs
- Integrated FET driver and bootstrap circuit
- Integrated accurate current sense for FOD
- Support various type of transmitter in WPC V1.2.4
  - BPP A11/A11a
  - BPP A6 with single coil or dual coil
  - EPP MPA2
  - EPP MPA5/MPA11 with additional DC-DC
- UVLO/OCP/SCP/OTP
- 4mm x 4mm FCQFN package

## 3 Applications

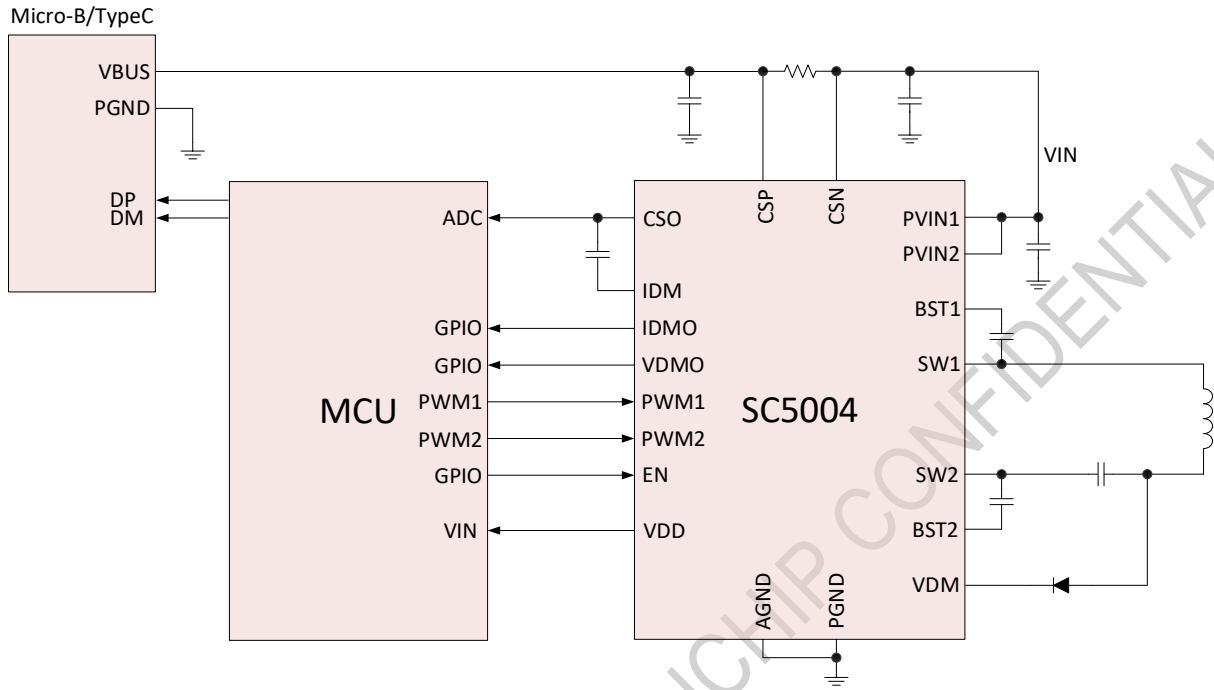
- WPC Compliant Wireless Power Transmitter
- Proprietary Wireless Chargers and Transmitter
- Medical and Wearable Applications

## 4 Device Information

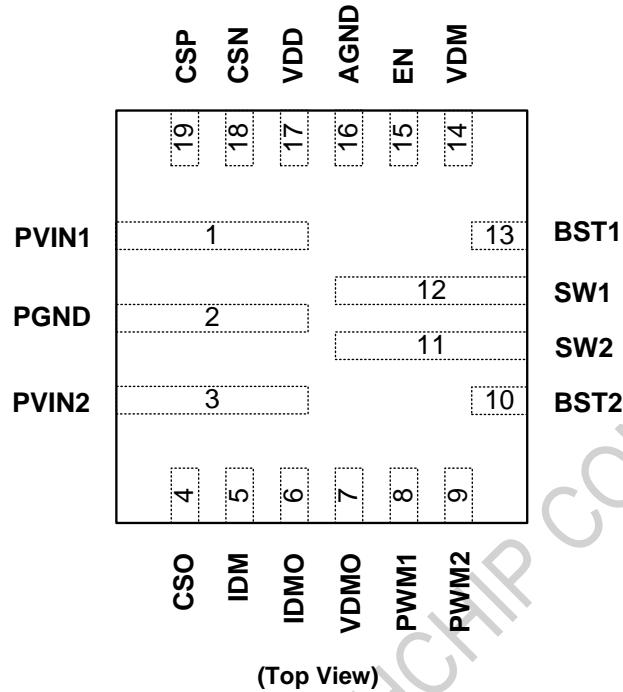
Part Number	Package	Dimension
SC5004QFER	FCQFN19L	4mm x 4mm x0.75mm



### 5 Typical Application Circuit



**6 Terminal Configuration and Functions**



TERMINAL		I/O	DESCRIPTION
NUMBER	NAME		
1	PVIN1	PWR	Input voltage for half-bridge MOSFET. Bypass with a 22 $\mu$ F ceramic capacitor to PGND.
2	PGND	GND	Power ground.
3	PVIN2	PWR	Input voltage for half-bridge MOSFET. Bypass with a 22 $\mu$ F ceramic capacitor to PGND.
4	CSO	O	Current sense amplifier output.
5	IDM	I	High-pass filter input. Current demodulation pin for data packets based on input current variation.
6	IDMO	O	Output of the demodulated 2-kHz communication signal based on current demodulation scheme.
7	VDMO	O	Output of the demodulated 2-kHz communication signal based on voltage demodulation scheme.
8	PWM1	I	PWM logic input for the Q1 and Q2 as shown in the Block Diagram. Logic HIGH turns on the high-side FET Q1, and turns off the low-side FET Q2. Logic LOW turns on the low-side FET Q2 and turns off the high-side FET Q1
9	PWM2	I	PWM logic input for the Q3 and Q4 as shown in the Block Diagram. Logic HIGH turns on the high-side FET Q3, and turns off the low-side FET Q4. Logic LOW turns on the low-side FET Q4 and turns off the high-side FET Q3
10	BST2	O	Connect a 0.1 $\mu$ F capacitor between BST2 and SW2 to bootstrap a voltage to provide the bias for high side MOSFET driver.



11	SW2	PWR	Switch node of the half-bridge MOSFET.
12	SW1	PWR	Switch node of the half-bridge MOSFET.
13	BST1	O	Connect a 0.1 $\mu$ F capacitor between BST1 and SW1 to bootstrap a voltage to provide the bias for high side MOSFET driver.
14	VDM	I	High-pass filter input. Voltage demodulation pin for data packets based on coil voltage variation.
15	EN	I	Enable pin. Logic LOW disables the IC. Logic HIGH enables the IC.
16	AGND	GND	Analog Ground.
17	VDD	O	Output of internal regulator to provide 5.0V power supply to internal gate drivers and control circuits. Connect a 2.2 $\mu$ F ceramic capacitor from VDD to AGND pin.
18	CSN	I	Negative end of input current sense amplifier.
19	CSP	I	Positive end of input current sense amplifier.



## 7 Specifications

### 7.1 Absolute Maximum Ratings

Over operating free-air temperature range (unless otherwise noted) <sup>(1)</sup>

		MIN	MAX	UNIT
Voltage range at terminals <sup>(2)</sup>	PVIN1, PVIN2, SW1, SW2, CSP, CSN	-0.3	15	V
	PWM1, PWM2, EN, CSO, VDM, IDM, VDMO, IDMO, VDD	-0.3	5.5	V
	BST1, BST2	-0.3	20.5	V
	SW1, SW2 (10ns transient)	-3	18	V
Temperature Range	Operating Junction, T <sub>J</sub>	-40	150	°C
	Storage temperature range, T <sub>stg</sub>	-65	150	°C

(1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values are with respect to network ground terminal.

### 7.2 Thermal Information

THERMAL RESISTANCE <sup>(1)</sup>		FCQFN19L	UNIT
Θ <sub>JA</sub>	Junction to ambient thermal resistance	TBD	°C/W
Θ <sub>JC</sub>	Junction to case resistance	8	°C/W

(1) Measured on JESD51-7, 4-layer PCB.

### 7.3 Handling Ratings

PARAMETER	DEFINITION	MIN	MAX	UNIT
ESD <sup>(1)</sup>	Human body model (HBM) ESD stress voltage <sup>(2)</sup>	-2000	2000	V
	Charged device model (CDM) ESD stress voltage <sup>(3)</sup>	-500	500	V

(1) Electrostatic discharge (ESD) to measure device sensitivity and immunity to damage caused by assembly line electrostatic discharges into the device.

(2) Level listed above is the passing level per ANSI, ESDA, and JEDEC JS-001. JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(3) Level listed above is the passing level per EIA-JEDEC JESD22-C101. JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 7.4 Recommended Operating Conditions

		MIN	TYP	MAX	UNIT
V <sub>PVIN1</sub> , V <sub>PVIN2</sub>	Input voltage range	4		13	V
C <sub>PVIN1</sub> , C <sub>PVIN2</sub>	PVIN1, PVIN2 Ceramic Capacitor		22		μF
C <sub>BST1</sub> , C <sub>BST2</sub>	BST1-SW1, BST2-SW2 Ceramic Capacitor		0.1		μF
C <sub>VDD</sub>	VDD Ceramic Capacitor		2.2		μF
T <sub>J</sub>	Operating junction temperature	-40		125	°C



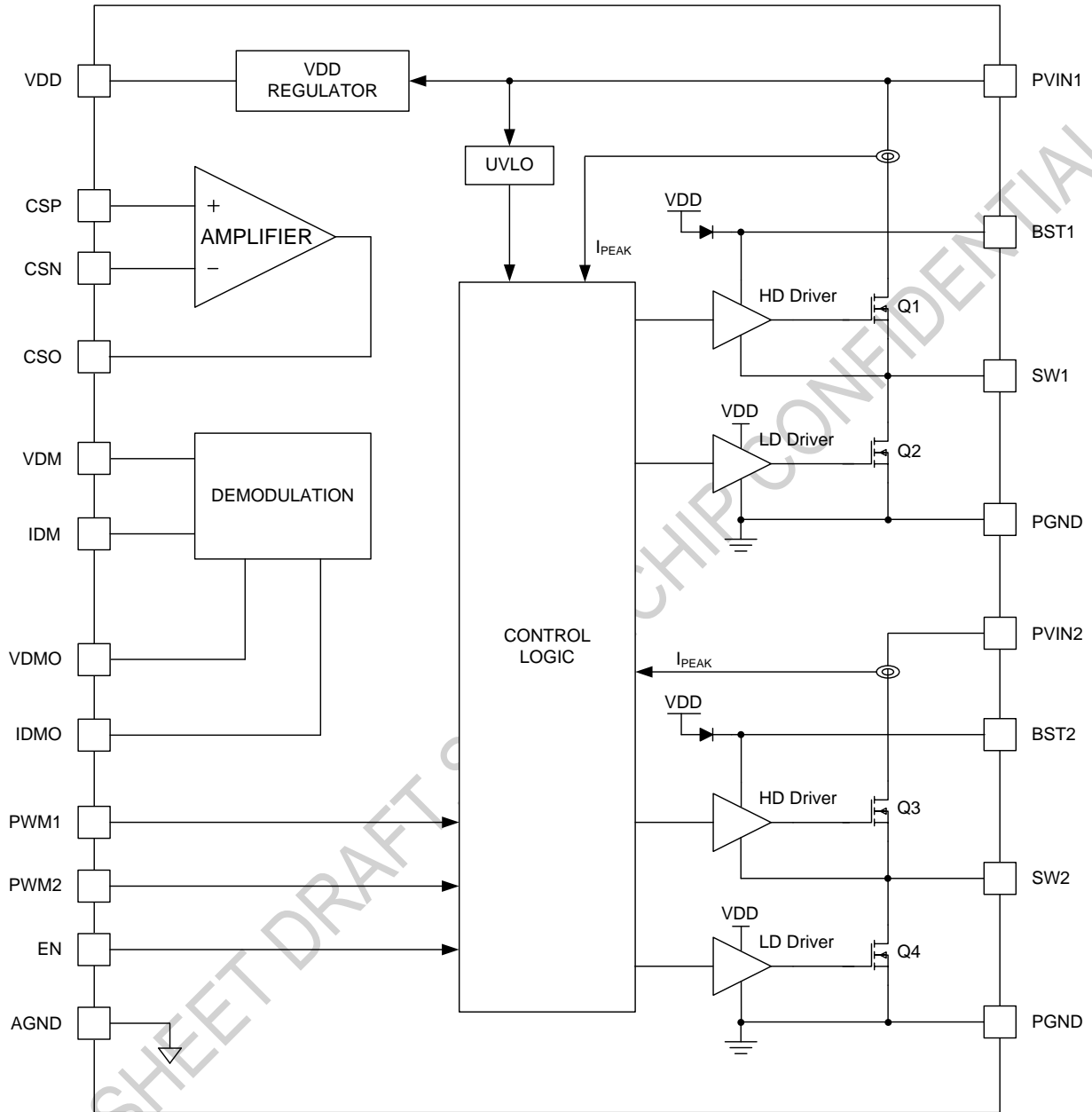
## 7.5 Electrical Characteristic

$T_J = 25^\circ\text{C}$  and  $V_{PVIN1} = 5.0\text{V}$ ,  $V_{PVIN2} = 5.0\text{V}$ , unless otherwise noted.

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>SUPPLY VOLTAGE</b>						
$V_{IN}$	Operating voltage		4		13	V
$V_{IN\_UVLO}$	Under voltage lockout threshold	Rising edge		3.6		V
		Falling edge		3.4		V
$I_Q$	Quiescent current into VIN	EN= high, no switching		0.38		mA
$I_{SD}$	Shutdown current into VIN	EN =low		40		$\mu\text{A}$
<b>VOLTAGE REGULATOR (VDD)</b>						
$V_{DD}$	VDD output voltage	$V_{IN} = 5.0\text{V}$ , $I_{VDD} = 10\text{mA}$		4.9		V
		$V_{IN} = 9.0\text{V}$ , $I_{VDD} = 10\text{mA}$		5		V
$I_{VDD\_LIM}$	VDD current limit	$V_{DD} = 5.0\text{V}$	30			mA
<b>CURRENT SENSE AMPLIFIER</b>						
G	Gain	Sense Resistor=20mohm; Sense Current=2A	49	50	51	V/V
$V_{OO}$	Output offset voltage	Measures at the CSO pin; $V_{CSP} = V_{CSN}$		0.5		V
<b>POWER SWITCH</b>						
$R_{DS(on)}$	SW1 High-side $R_{DS(on)}$	$V_{DD} = 5.0\text{V}$		17		m $\Omega$
	SW1 Low-side $R_{DS(on)}$	$V_{DD} = 5.0\text{V}$		17		m $\Omega$
	SW2 High-side $R_{DS(on)}$	$V_{DD} = 5.0\text{V}$		17		m $\Omega$
	SW2 Low-side $R_{DS(on)}$	$V_{DD} = 5.0\text{V}$		17		m $\Omega$
<b>SHORT CIRCUIT PROTECTION</b>						
$I_{LIM}$	High-side current limit threshold			10		A
$T_p$	Hiccup period			10		ms
<b>EN, PWM1, PWM2</b>						
$V_{IH}$	Input logic high		2.4			V
$V_{IL}$	Input logic low				0.4	V
<b>VDMO, IDMO</b>						
$V_{OH}$	Output logic high		$0.9 \cdot V_{DD}$			V
$V_{OL}$	Input logic low				$0.1 \cdot V_{DD}$	V
<b>THERMAL SHUTDOWN</b>						
$T_{SD}$	Thermal shutdown temperature			165		$^\circ\text{C}$
	Thermal shutdown hysteresis			15		$^\circ\text{C}$



### 8 Functional Block Diagram



## 9 Feature Description

### 9.1 Current Sense Amplifier

To support foreign object detection (FOD), the SC5004 senses the average input current to the device. The integrated current sense amplifier has voltage gain of 50. For proper scaling of the current signal, the recommended current sense resistor is 10mΩ/20mΩ.

The current sense amplifier output has a typical 0.5V offset when the sensed current is zero. For accurate measurement of the input current, MCU need to calibrate this offset.

### 9.2 PWM Control

The PWM1 input controls the internal MOSFET Q1 and Q2, and the PWM2 input controls the internal MOSFET Q3 and Q4 as shown in the Block Diagram. The PWM1 and PWM2 can independently control the SW1 and SW2 duty cycle and frequency. Please be noted that dead time has already been implemented between Q1 (or Q3) and Q2 (or Q4) internally, so there is no need for dead time between external control signals PWM1 and PWM2.

### 9.3 Under-Voltage Lockout (UVLO)

The UVLO function protects the chip from operating at insufficient power supply. The chip disables all the function if input voltage is lower than 3.4V (typical) and it doesn't start up again until input voltage is higher than 3.6V (typical).

### 9.4 Voltage Regulator

The SC5004 has an integrated low-dropout (LDO) voltage regulator. The internal power drivers and control circuits are powered from this voltage. The VDD pin supplies a regulated 5.0V voltage supply. Decouple this pin to power ground with a 2.2μF low ESR ceramic capacitor placed close to the IC.

The VDD regulator is enabled once PVIN is above the UVLO threshold. It is not controlled by the EN signal. The load capability of VDD regulator is about 20mA, so it can be used to power up MCU directly.

### 9.5 Voltage Demodulation

In order to increase the communication reliability in any load condition, the SC5004 has integrated two demodulation schemes, one based on input average current information and the other based on coil voltage information. The voltage mode envelope detector is

implemented using a discrete solution as depicted on Figure1. This simple implementation achieves the envelope detector function low-pass filter as well as the DC filter function.

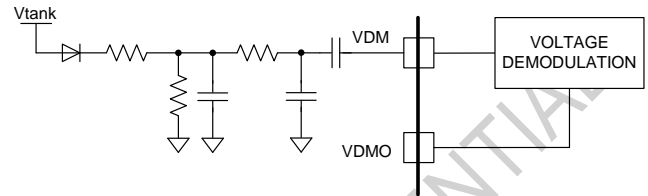


Fig1. Voltage Demodulation

### 9.6 Current Demodulation

The current-mode detector takes the modulation information from the average input current. The capacitor between CSO and IDM pin can filter the DC current. The MCU can detect the demodulation results on VDMO and IDMO pins and then implement the packet decode. The MCU can select either voltage-mode or current-mode signals depending upon which produces the best demodulated signal.

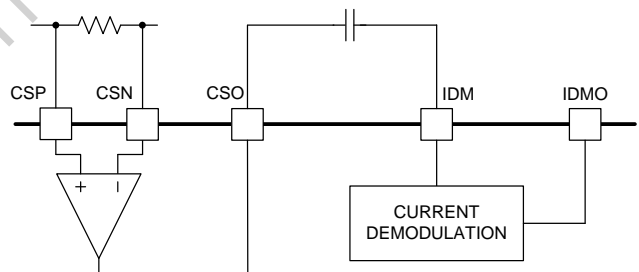


Fig2. Current Demodulation

### 9.7 Over-Current Protection (OCP)

The SC5004 integrates a hiccup mode over-current protection. Current of the SW1 high-side FET and SW2 high-side FET are sensed and compared to the current-limit threshold during every switching cycle. When the sensed current reaches the current-limit threshold, the over-current fault counter is incremented. If the over-current fault counter reaches 8 and overflows, all 4 internal FETs are turned off regardless of the PWM inputs. The IC remains in hiccup mode for a period equal to 10ms typically and then attempts to restart. The hiccup mode OCP protection can reduce the average current greatly to alleviate the thermal issue and to protect the converter. Once the OCP condition is removed, SC5004 exits hiccup mode and goes back to normal operation.





### **9.8 Over Temperature Protection (OTP)**

The over temperature protection (OTP) prevents the chip from operating at exceedingly high temperatures. When the silicon die temperature exceeds 165°C, SC5004 is shut down. When the temperature drops below threshold (typically 150°C), the chip is enabled again.

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## 10 Application Information

### 10.1 Input Current Sense

The SC5004 senses the average input current to the device. The recommended current sense resistor is 10mΩ/20mΩ. Resistor of 1% or higher accuracy and low temperature coefficient is recommended.

The resistor power rating and temperature coefficient should also be considered. The power dissipation is roughly calculated as  $P=I^2R$ , and  $I$  is the highest current flowing through the resistor. The resistor power rating should be higher than the calculated value.

The current sense amplifier output has a typical 0.5V offset when the sensed current is zero. Please be noted that this offset may vary a little from one chip to another, so when MCU is calibrating this offset, it is highly recommended to use ADC to sense this offset instead of using fixed 0.5V.

Figure 3 shows the internal current sense output (CSO) voltage over the sensed current based on different sense resistor. Since the integrated current sense amplifier has voltage gain of 50V/V, if input current is sensed on a 10mΩ resistor, the voltage to current gain will be 0.5V/A. If input current is sensed on a 20mΩ resistor, the voltage to current gain will be 1V/A.

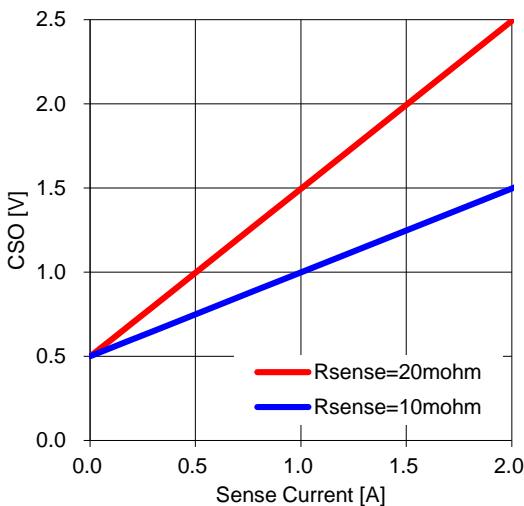


Fig3. CSO Voltage over Sense Current

### 10.2 Voltage/Current Demodulation

SC5004 integrates simultaneous voltage and current demodulation based on coil voltage and input average current separately. Compared with the discrete demodulation solution, SC5004 need much less number of external components.

Figure4 shows a typical circuit for voltage demodulation. D1/R3/R5/C4 is an envelope demodulation of the LC tank voltage. R2/C3 is a RC filter which can filter the high frequency switching noise while keep the 2 kHz communication signal. C2 is a DC blocking capacitor which passes through only the ac signal to the internal demodulator.

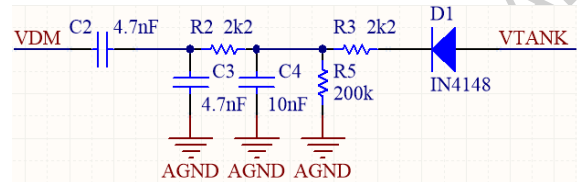


Fig4. Voltage Demodulation

Figure5 shows a typical communication packet, which is comprised of a preamble, a header, the actual message, and a checksum, as defined by the WPC standard.

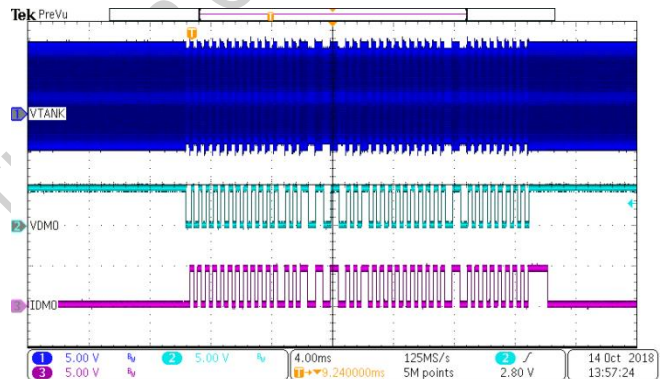


Fig5. VDMO/IDMO Demodulation Output



## 11 Layout Guide

Here are the guidelines to follow:

- Make routing loop as small as possible, especially the power loop, to minimize EMI noises.
- Widen the copper between SW1, SW2 and LC tank, because high current in the LC tank can cause power losses on the traces and hence low efficiency. Moreover, the PVIN1/2 routing should be as wide as possible.
- The input current sense traces should be connected to the current sense resistor's pads in Kelvin sense way as below, and routed in parallel (differential routing).
- Place small-size input capacitors as close as possible between the PVIN1/2 pins and PGND pin. These capacitors can effectively filter out high-frequency noises due to their low ESR and ESL. Please refer to C8 and C11 in Figure 6.
- Separate the analog-ground plane from the power-ground plane, and use only one point to join them. Please refer to Figure 7.
- Keep analog-ground plane and power-ground plane low impedance. Use as much copper as possible.

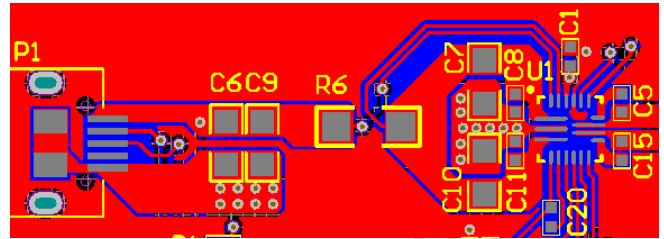


Fig6. Top Layer

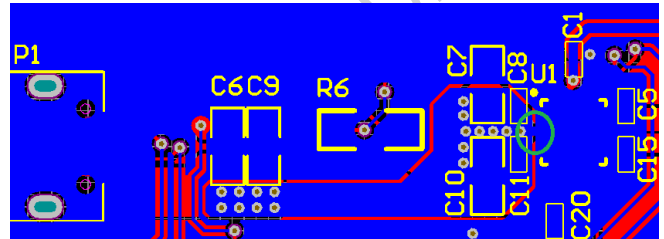
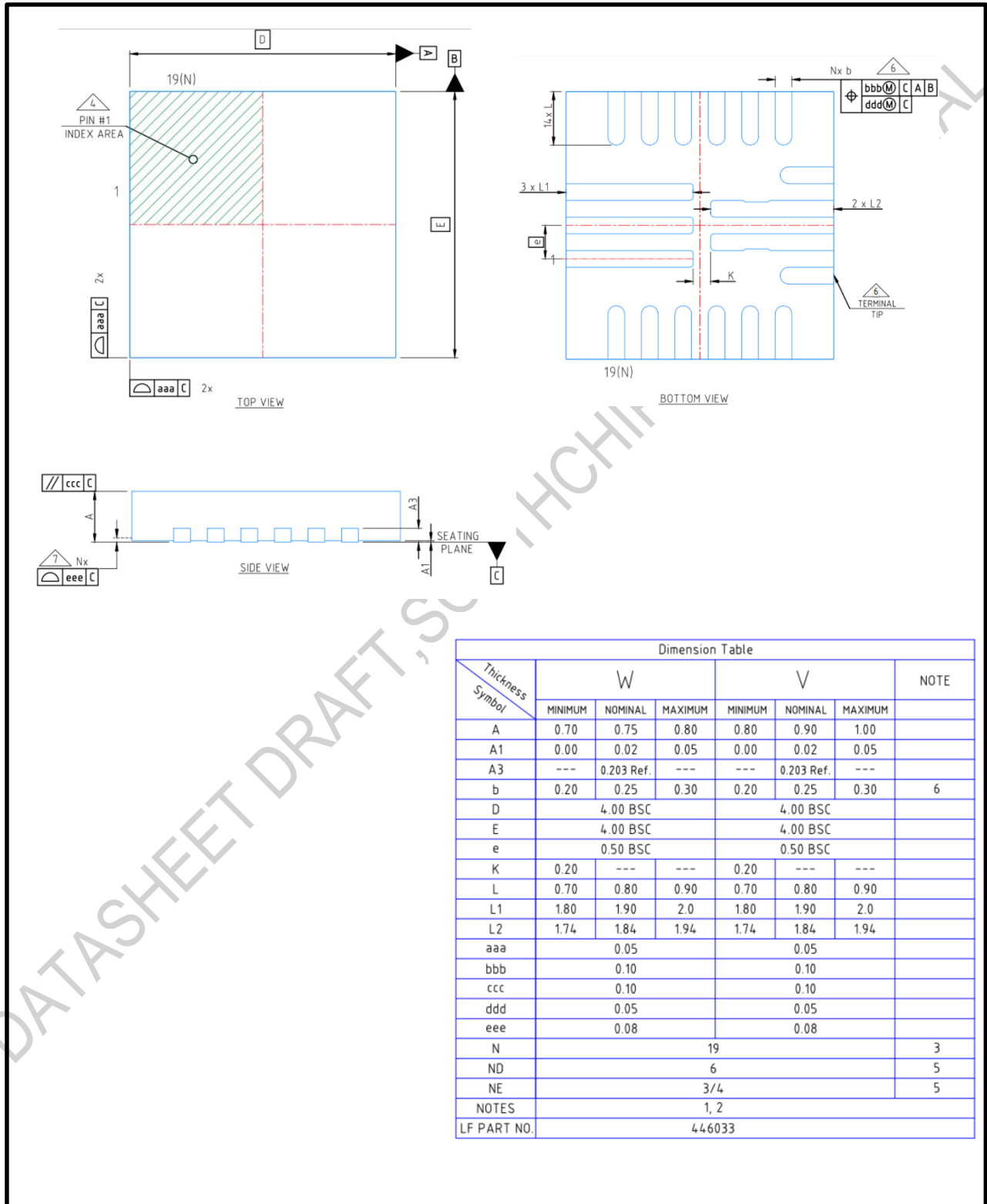


Fig7. Bottom Layer



12 MECHANICAL DATA

FCQFN19L (4x4x0.75)



单击下面可查看定价，库存，交付和生命周期等信息

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